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(54) **NON-VOLATILE MEMORY DEVICE WITH PLURAL REFERENCE CELLS, AND METHOD OF SETTING THE REFERENCE CELLS**

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**G11C 16/04** (2006.01)

(52) **U.S. Cl.**  
USPC ..... **365/185.2**; 365/185.21; 365/185.22; 365/185.28

(58) **Field of Classification Search**  
USPC ..... 365/185.5, 185.21, 185.22, 185.28  
See application file for complete search history.

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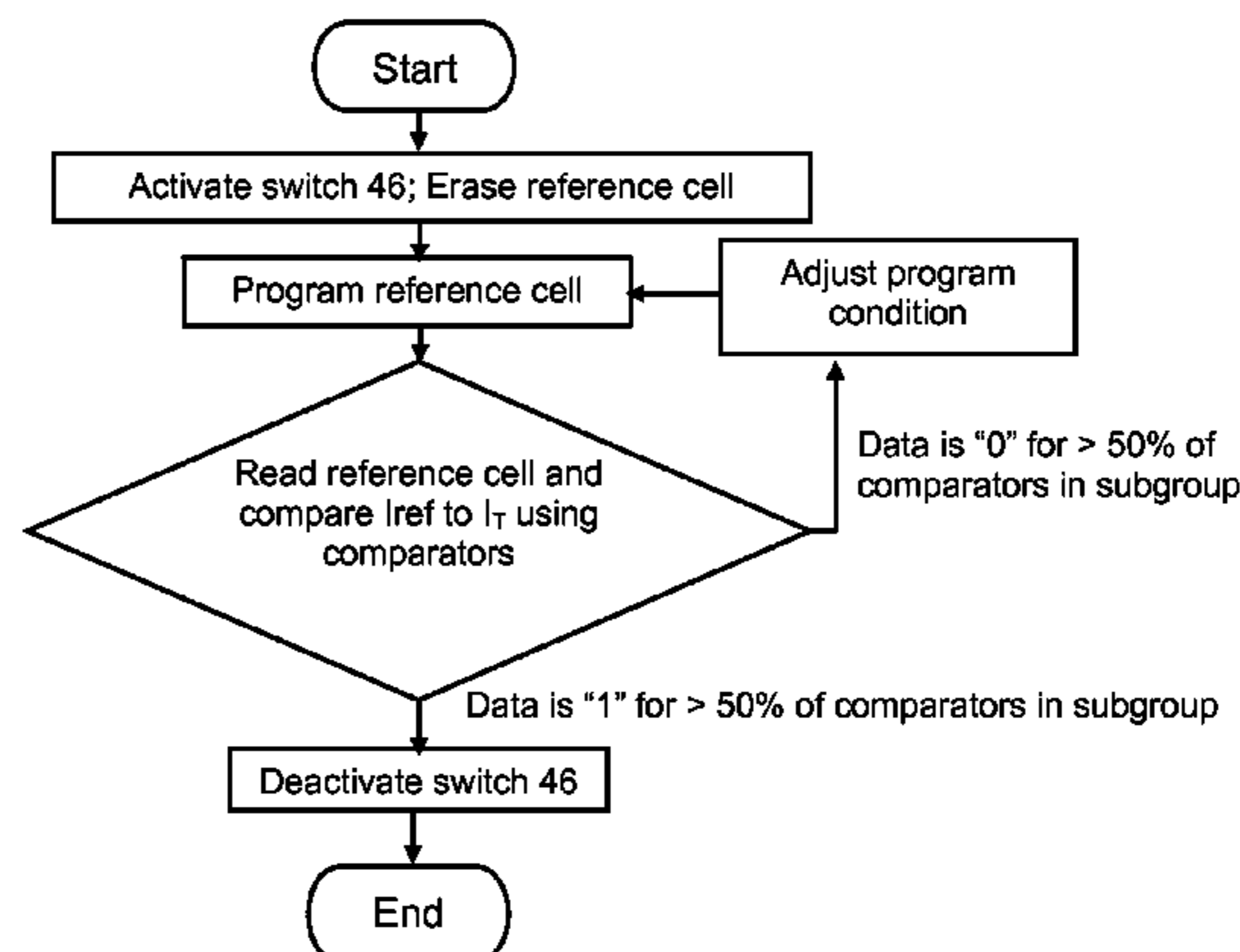
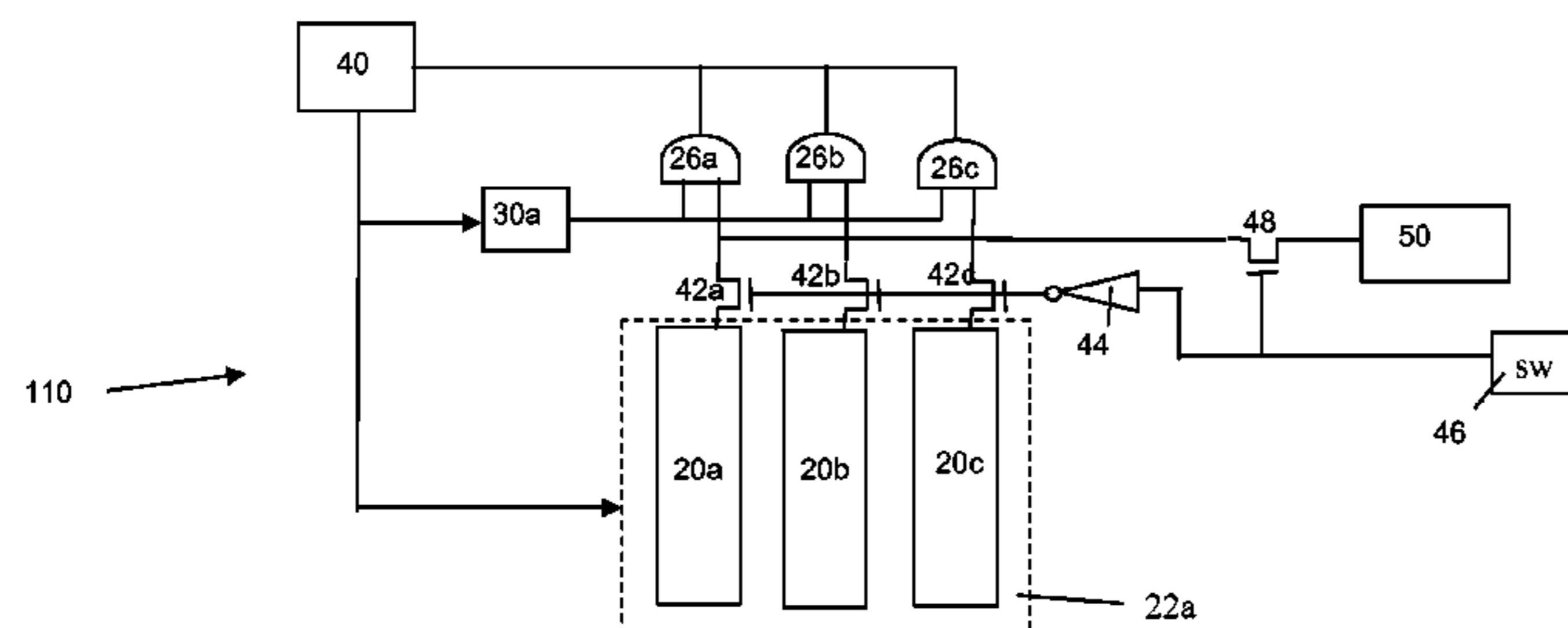
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(57) **ABSTRACT**

A non-volatile memory device has an array of non-volatile memory cells, a first plurality of non-volatile memory reference cells, with each reference cell capable of being programmed to a reference level different from the other reference cells; and a second plurality of comparators. Each of the comparators is connectable to one of the first plurality of non-volatile memory reference cells and to one of a third plurality of memory cells from among the array of non-volatile memory cells.

**8 Claims, 4 Drawing Sheets**



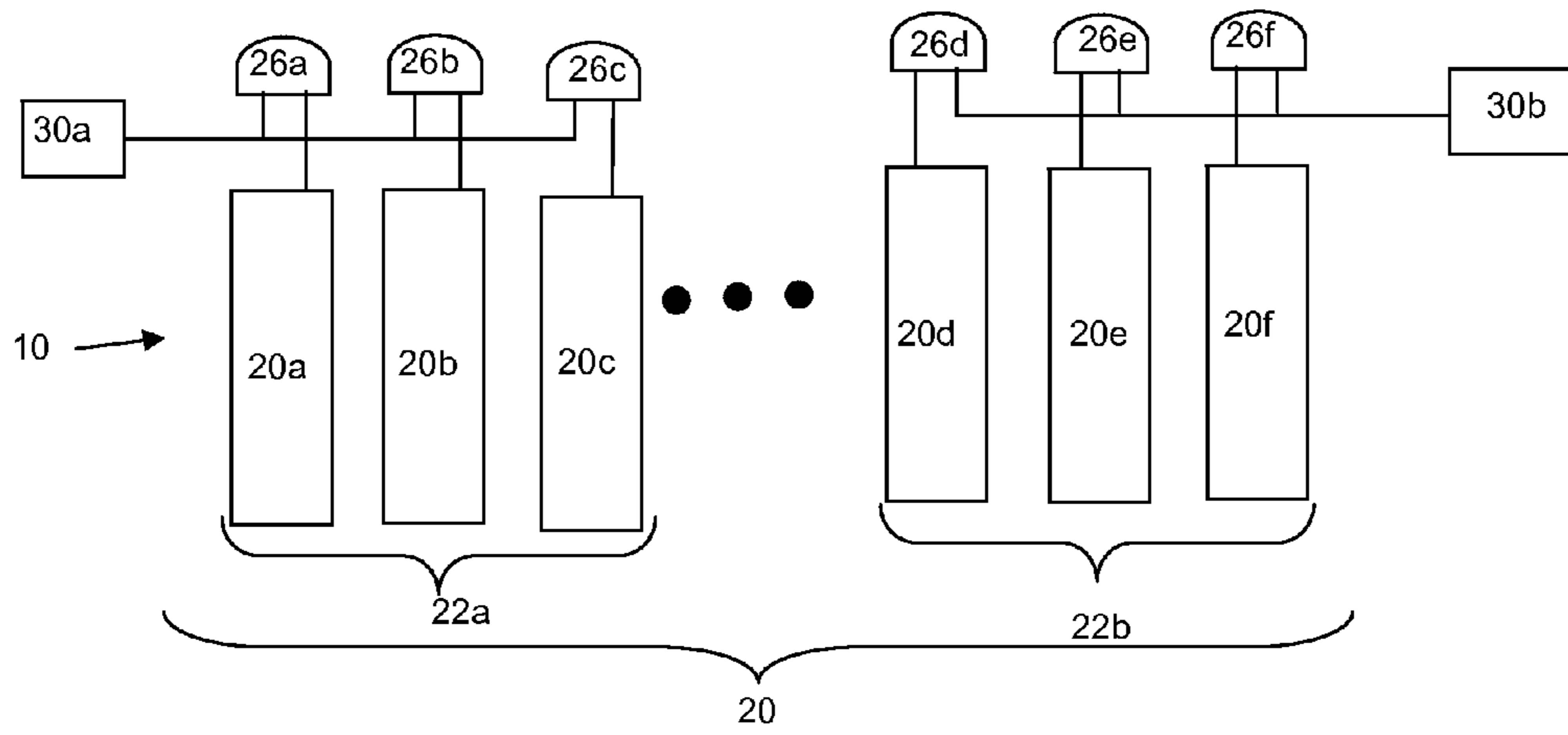


Figure 1

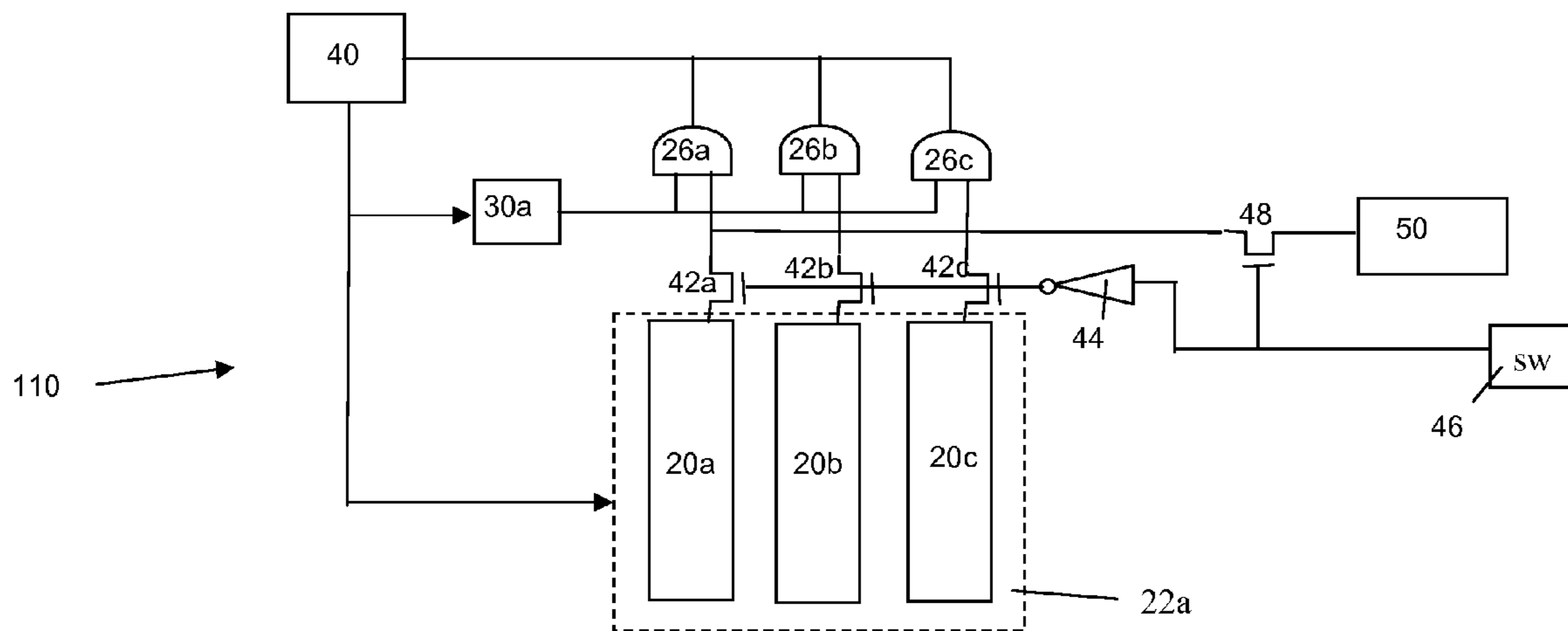


Figure 2A

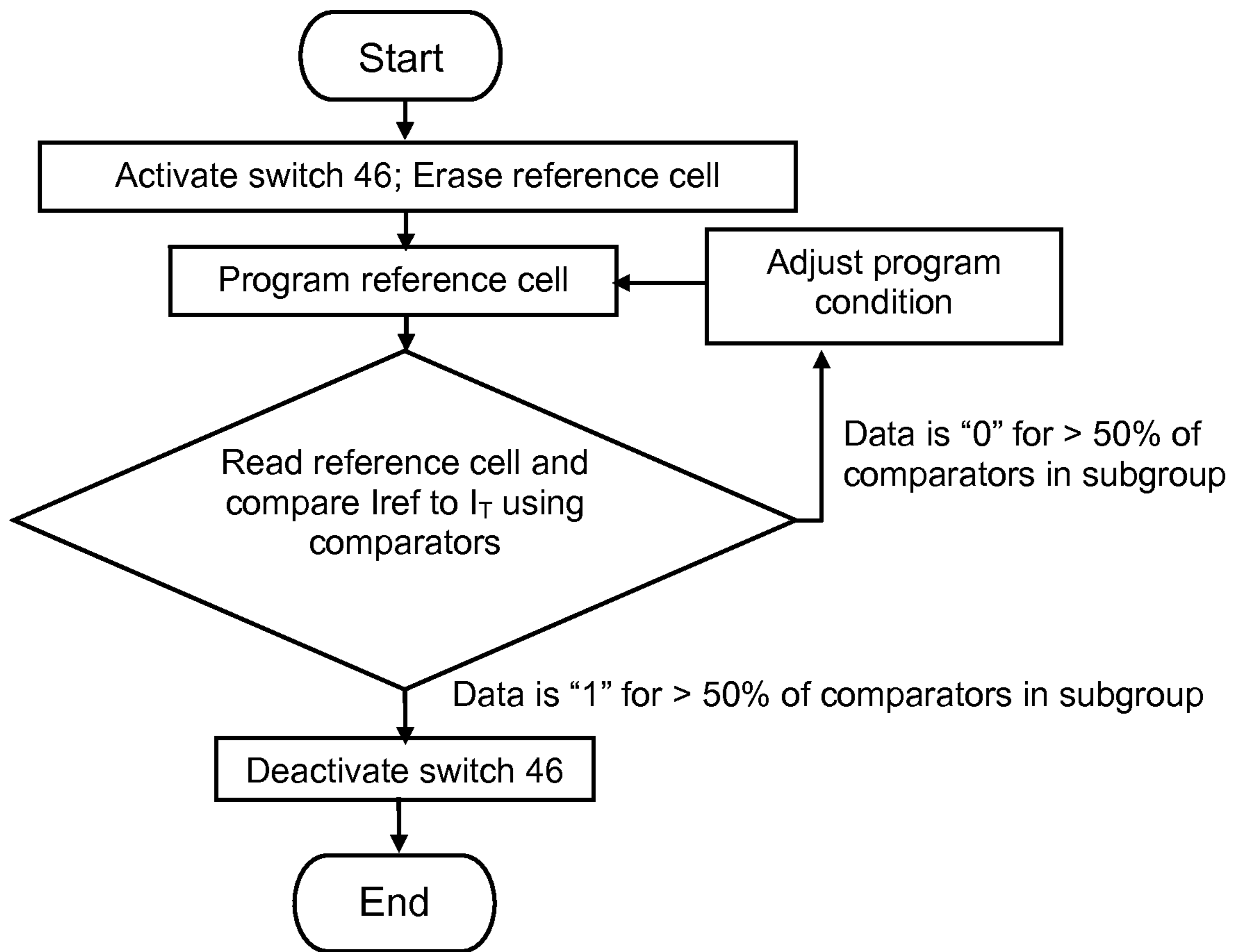


Figure 2B

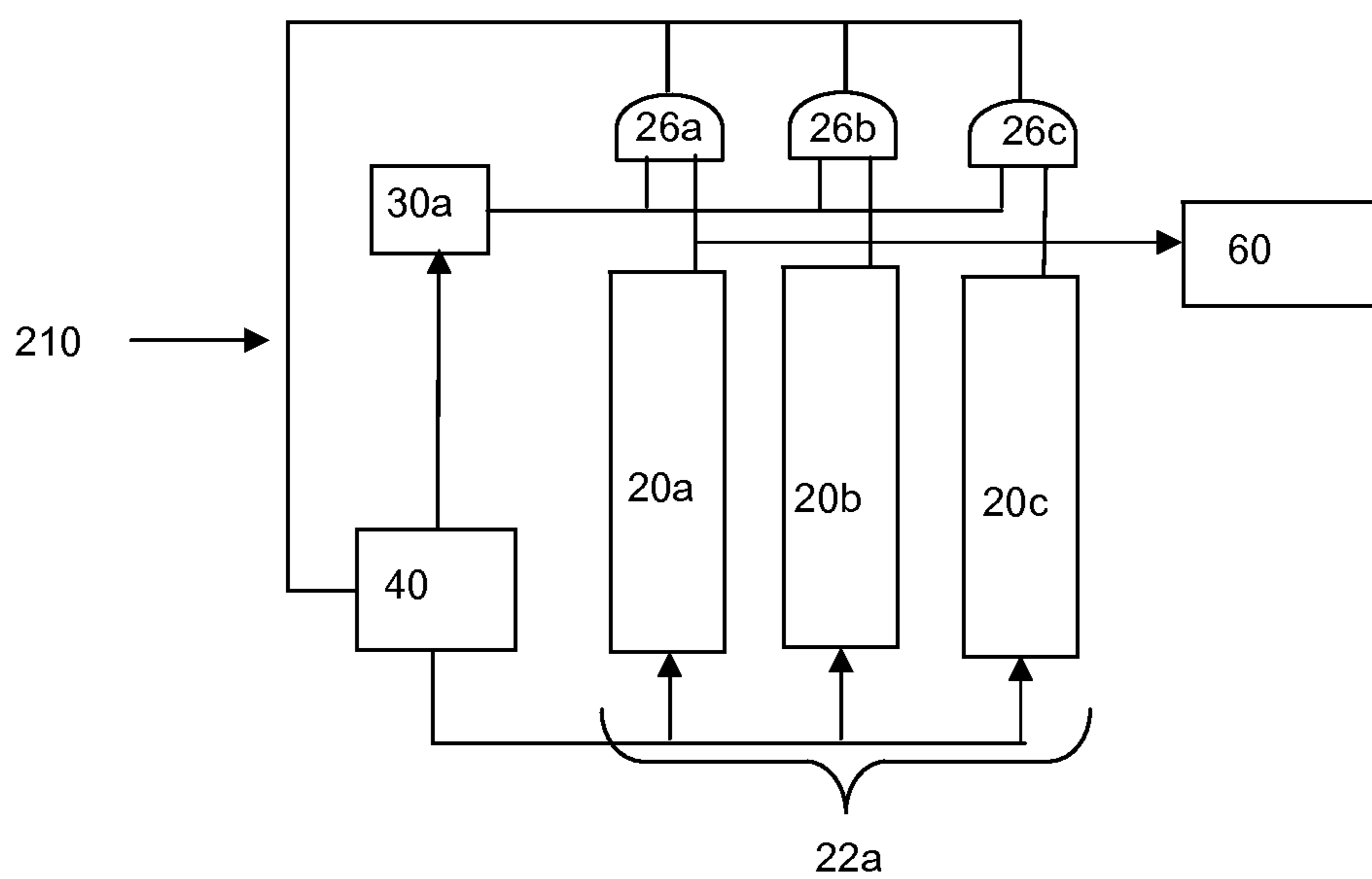


Figure 3A

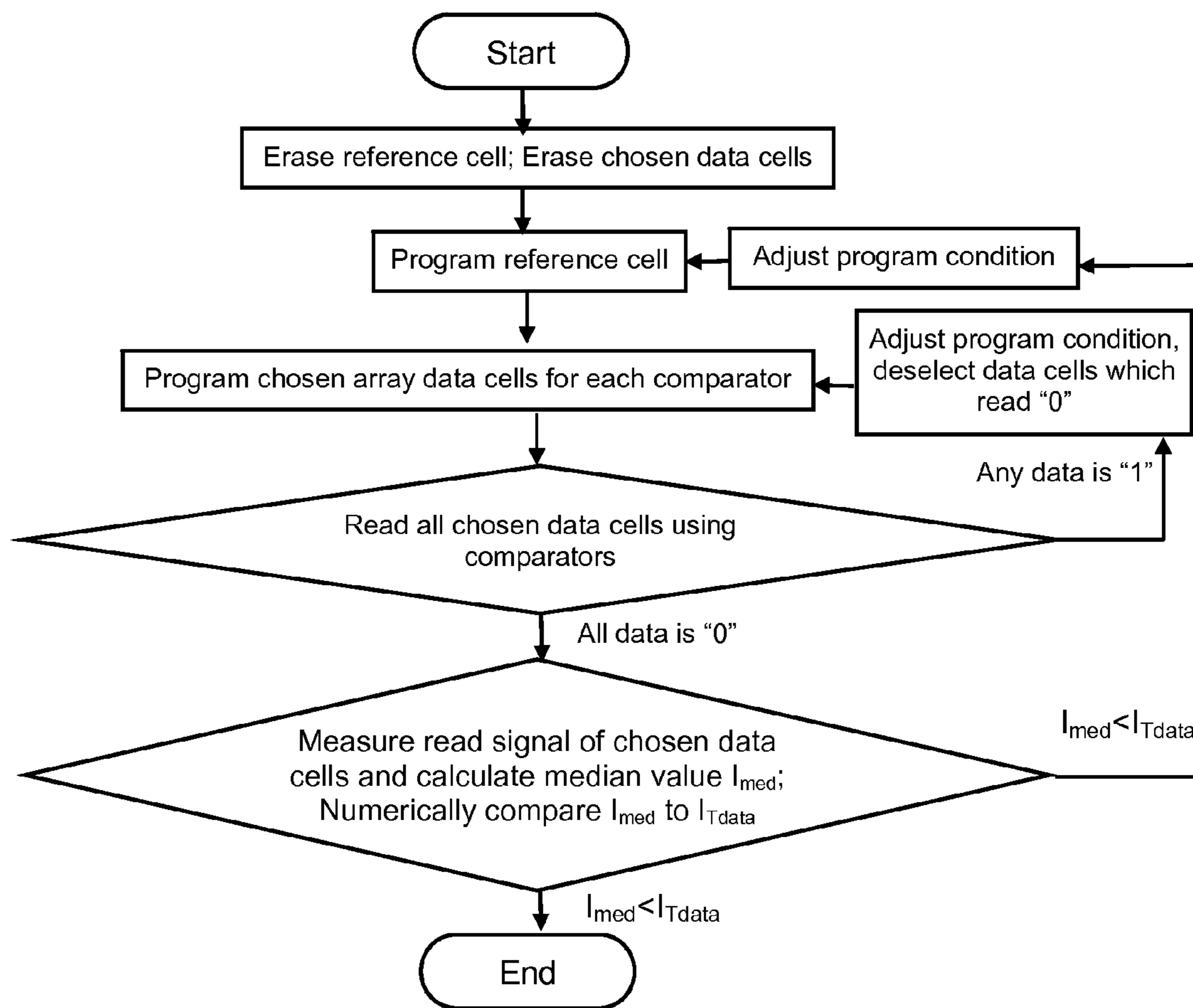


Figure 3B

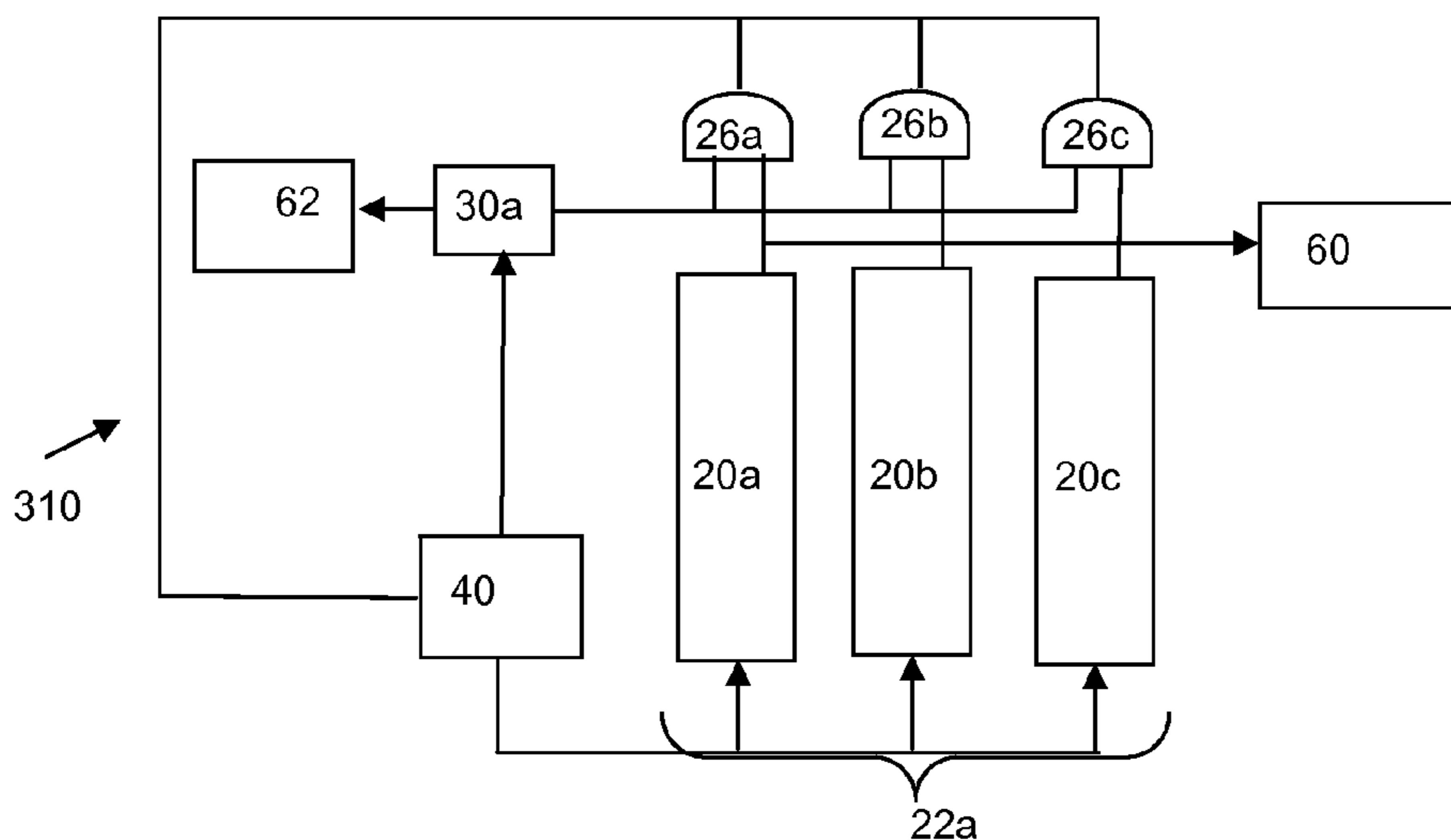


Figure 4A

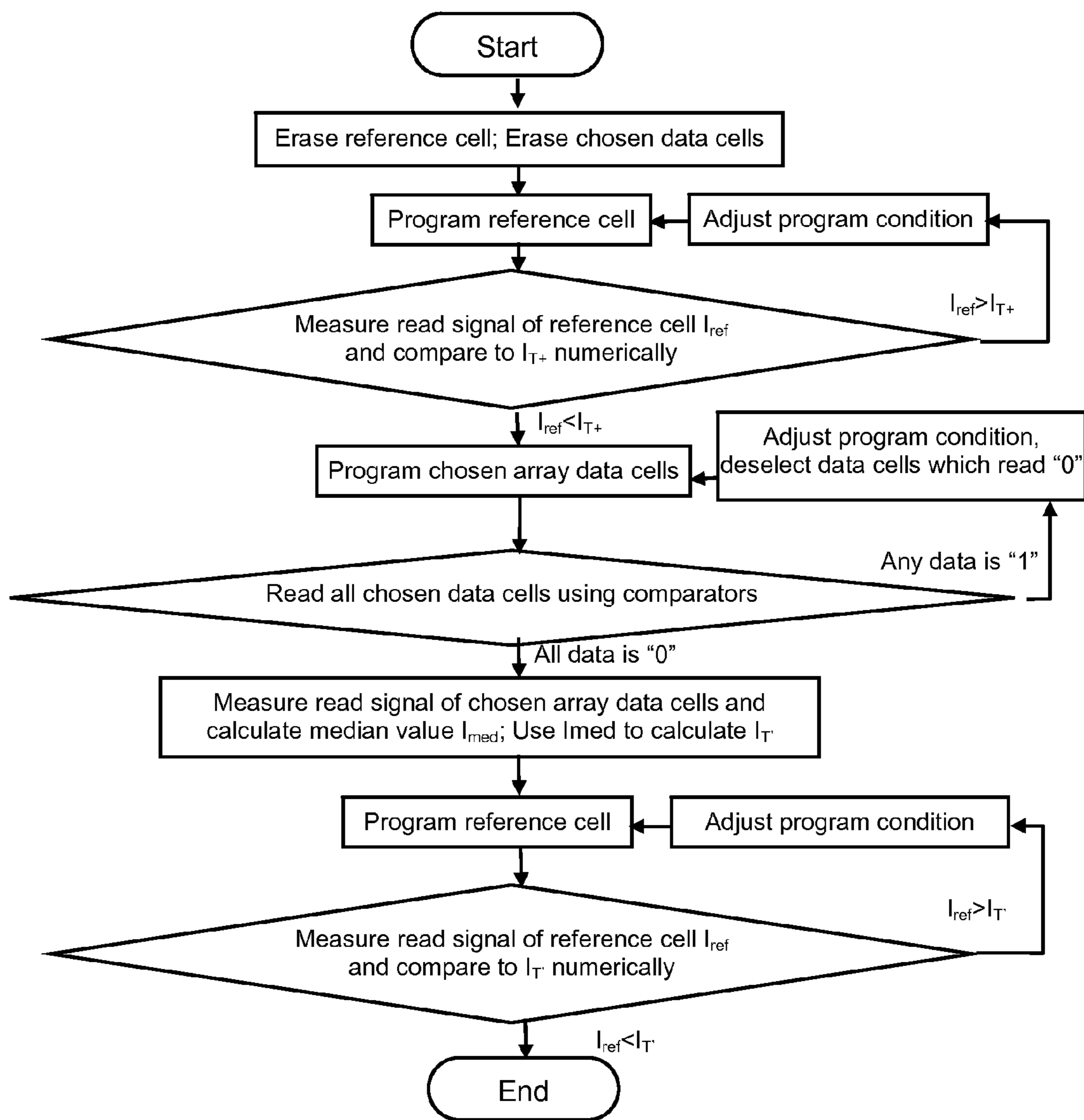


Figure 4B

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# NON-VOLATILE MEMORY DEVICE WITH PLURAL REFERENCE CELLS, AND METHOD OF SETTING THE REFERENCE CELLS

## CROSS REFERENCE TO RELATED APPLICATIONS

This application is a divisional of U.S. application Ser. No. 12/040,732, filed Feb. 29, 2008, which is incorporated herein by reference.

## TECHNICAL FIELD

The present invention relates to a nonvolatile memory device and more particularly to a non-volatile memory device with an array of non-volatile memory cells with a plurality of non-volatile reference cells wherein each reference cell is capable of being programmed to a different level from the other reference cells.

## BACKGROUND OF THE INVENTION

A non-volatile memory device having an array of non-volatile memory cells is well known in the art. Typically, a device also has a number of non-volatile reference memory cells provided with the array. In addition, typically, multiple comparators are provided with the array of non-volatile memory cells to provide for parallel reading. Each comparator is associated with a group of the non-volatile memory cells in the array. Further, each comparator is connected to one of the reference cells, and uses the signal from the reference cell and compares it to the associated group of memory cells. Finally, in the prior art, all of the comparators are either all connected to a single non-volatile memory reference cell or all of the comparators are connected to a number of non-volatile memory reference cells wherein all of the non-volatile memory reference cells are set to the same targeted signal value.

Because of process variations, and other anomalies, the I-V (current-voltage) characteristics of individual transistors in the comparators will have different offsets and cause the comparators to have different "effective reference levels". This results in the operating window being larger than otherwise necessary to take into account such large difference in the reference levels.

## SUMMARY OF THE INVENTION

Accordingly, in the present invention, a non-volatile memory device has an array of non-volatile memory cells and a first plurality of non-volatile memory reference cells. Each of the non-volatile reference cells is capable of being programmed to a reference level different from the other reference cells. In addition, the memory device comprises a second plurality of comparators. Each of the comparators is connectable to one of the first plurality of non-volatile memory reference cells and to one of a third plurality of memory cells from among the array of non-volatile memory cells.

The present invention also relates to methods for programming the non-volatile reference cells to selected target values.

## BRIEF DESCRIPTION OF THE DRAWINGS

FIG. 1 is a schematic block level diagram of a memory device of the present invention.

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FIG. 2A is a schematic block level diagram of one embodiment of the memory device of the present invention showing the programming of the reference cells. FIG. 2B is a flowchart showing the method of programming the reference cells in accordance with the embodiment shown in FIG. 2A.

FIG. 3A is a schematic block level diagram of another embodiment of the memory device of the present invention showing the programming of the reference cells. FIG. 3B is a flowchart showing the method of programming the reference cells in accordance with the embodiment shown in FIG. 3A.

FIG. 4A is a schematic block level diagram of yet another embodiment of the memory device of the present invention showing the programming of the reference cells. FIG. 4B is a flowchart showing the method of programming the reference cells in accordance with the embodiment shown in FIG. 4A.

## DETAILED DESCRIPTION OF THE INVENTION

Referring to FIG. 1, there is shown a block level diagram of a memory device 10 of the present invention. The device 10 comprises an array 20 of non-volatile memory cells. As is well known, the array 20 of non-volatile memory cells is arranged in a plurality of rows and columns, although one skilled in the art would appreciate that the term "row" and "column" may be interchanged. Further, the array 20 is divided into a plurality of groups (although only 2 groups 22a and 22b are shown, it is clear to those skilled in the art, that the array 20 may be divided into more than 2 groups). Further, within each group, e.g. 22a, the group is subdivided yet into a plurality of subgroups, e.g. 20a, 20b and 20c of non-volatile memory cells. Further, each subgroup, e.g. 20a, may comprise a plurality of non-volatile memory cells. The non-volatile memory cells that form the subgroup of cells 20a, 20b or 20c, may be stack gate floating gate, split gate floating gate, or use charge trapping layer; or use phase changing material. Further, each of the cells may be a Single Level Cell (SLC) storing a single bit or a Multi-Level Cell (MLC) storing a plurality of bits. Similarly, the group 22b comprises a plurality of subgroups 20d, 20e, and 20f, each of which may comprise a plurality of non-volatile memory cells. A comparator 26, e.g. 26a, is associated with a subgroup, e.g. 20a of non-volatile memory cells. Finally, a reference non-volatile memory cell 30 is associated with each group 22 of non-volatile memory cells, and the associated comparators 26(a-c). Alternatively, each comparator 26 may have a different reference cell 30 associated therewith. In the preferred embodiment, the reference cell 30 is of the same structure as the non-volatile memory cells in the array 20. Thus, the circuits to program, erase, and read the non-volatile memory cells in the array 20 can also be used for the reference cells 30. Each comparator, e.g. 26a has one input connected to the reference non-volatile memory cell, e.g. 30a, and the other input connectable to one of the non-volatile memory cells 20 from the subgroup 20a, with which the comparator 26a is associated.

Unlike the prior art, each of the reference memory cells 30 is programmed to a read signal (which may be a voltage signal  $V_{ref}$  or a current signal  $I_{ref}$  depending on the characteristics of the non-volatile memory cell and the method used to read it) different from the other reference memory cell 30. This difference is used to compensate for the read offset  $I_{offset}$  or  $V_{offset}$  resulting from process and other variations in the individual comparators. In the case where the read signal is a current signal,  $I_{ref} = I_T + I_{offset}$ . In the case where read signal is a voltage signal,  $V_{ref} = V_T + V_{offset}$ .  $I_T$  or  $V_T$  is the target effective reference level which differentiates between data "0" and "1" in memory data cells. This level is generally selected based on

memory cell and sensing circuit characteristics. Thus, process variations during the manufacturing of the device 10, (especially for the comparators 26 (a-c) associated with reference cell 30a and comparators 26(d-f) associated with reference cell 30b) may be compensated by being able to program each reference cell 30 to a different level. In this manner, the operating window for the device 10 may be tightened.

To program each of the non-volatile reference memory cell 30 to a different read signal than the other non-volatile reference memory cell 30 in order to compensate for comparator offsets, there are three methods.

Referring to FIG. 2A there is shown a block level diagram of the device 110 capable of performing the first method of the present invention. The device 110 is similar to the device 10 and hence, like numerals will be used to designate like parts. The device 110 has an array 20 of non-volatile memory cells, divided into a plurality of subgroups of non-volatile memory cells 20(a-c) formed in a group 22a. Although only three subgroups 20(a-c) are shown forming one group 22a, it is clear that there are other groups 22x, with other subgroups 20x forming the array 20 of non-volatile memory cells. In addition, each subgroup, e.g. 20a has an associated comparator 26a. Finally a reference cell 30a is associated with the group 22a of non-volatile memory cells, similar to that described and shown in FIG. 1.

A read out signal from non-volatile memory cells from each subgroup, e.g. 20a is supplied, along the bit line, to one input of the associated comparator, e.g. 26a through an associated switch 42a. Another input to each of the comparators 26(a-c) is supplied from the reference cell 30a. During the read operation, the comparator 26 generates data "0" if the read signal from the one input represents over-programmed state as compared to the read signal from the other input (e.g.  $I_{data} < I_{ref} - I_{offset}$ ), and data "1" if otherwise. The output data of each comparator 26 is supplied to a programming circuit 40, which controls the programming of the reference cell 30 and of data cells in the array 20. The one input of each comparator 26 is also connected to a source 50 (either current source or voltage source) through another switch 48. The source 50 is set to the target effective reference level  $I_T$  or  $V_T$ . The source 50 can be a circuit on board with the integrated circuit device 110 or it can be supplied external to the device 110, as in for example, a pad used during testing. An inverter 44 is connected to the switches 42(a-c). A switch signal 46 is supplied to the inverter 44 and the other switch 48.

In operation, the switch signal 46 is first activated such that the transistor 48 is on and transistors 42(a-c) are off, thereby causing the signal from the source 50 to be supplied to each of the comparators 26. The reference cell 30a is erased. The programming circuit 40 then weakly programs the reference cell 30a. As used herein, the condition of this initial program operation (i.e. weakly program) is chosen so that the reference cell 30a is not over-programmed, as verified by a subsequent read which is discussed below. A read operation of the reference cell 30a is performed and the read signal is compared to the signal from the source 50 using the comparators 26(a-c). If the reference cell 30a is current based, the current  $I_{ref}$  read from the reference cell 30a is compared to the current  $I_T$  from the source 50. In the event that the reference cell 30a is under programmed (i.e. data="0", corresponding to  $I_{ref} > I_T + I_{offset}$ ) for more than 50% of the comparators 26 in the group 22a with which the reference cell 30a is associated, then the programming circuit 40 causes further programming of the reference cell 30a.

When additional programming of the reference cell 30a occurs, the conditions of programming may be changed so that the rate of electron injection for programming remains

the same as previously, thereby maintaining a substantially constant rate of electron injection. As is well known to those skilled in the art, the condition of under programming of  $I_{ref} > I_T + I_{offset}$  is caused by more current flowing in the channel of the reference cell 30a, due to less electrons being stored on the floating gate. Of course, with other types of non-volatile memory cells, the condition of under programming may not necessarily result in  $I_{ref} > I_T + I_{offset}$ . Once the reference cell 30a is programmed to the correct state, (i.e. data="1", corresponding to  $I_{ref} < I_T + I_{offset}$ , for more than 50% of the comparators 26 in the group 22a with which the reference cell 30a is associated) programming of the reference cell 30a is completed. Other reference cells 30 in the circuit are programmed similarly. Programming of multiple reference cells 30 can be done in parallel or in series. When reference cells 30 are programmed in parallel, those reference cells 30 which have passed verification are deselected to prevent them from being programmed further, while programming continues for those reference cells 30 which have not passed verification. Once programming of all reference cells 30 is completed, the switch signal 46 is reversed to prepare for normal data write and read operations. This causes the switch 48 to be turned off, and transistors 42(a-c) to be turned on, resulting in the one input for each comparator 26 being supplied with the signal from the non-volatile memory data cells in the subgroup 20 with which the comparator 26 is associated. A flow chart of this method is schematically shown in FIG. 2B.

Referring to FIG. 3A there is shown a block level diagram of the device 210 capable of performing the second method of the present invention. The device 210 is similar to the device 110 and device 10 and hence, like numerals will be used to designate like parts. The device 210 has an array 20 of non-volatile memory cells, divided into a plurality of subgroups of non-volatile memory cells 20(a-c) formed in a group 22a. Although only three subgroups 20(a-c) are shown forming one subgroup 22a, it is clear that there are other groups 22x, with other subgroups 20 forming the array 20 of non-volatile memory cells. In addition, each subgroup, e.g. 20a has an associated comparator, e.g. 26a. Finally a reference cell 30a is associated with the group 22a of non-volatile memory cells, similar to that described and shown in FIGS. 1 and 2A.

Read out from non-volatile memory cells from each subgroup, e.g. 20a is supplied, along the bit line, to one input of the associated comparator, e.g. 26a. In addition, the read out is supplied to a source 60 such as an output bonding pad, such that the read-out may be measured. Another input to each of the comparators 26(a-c) is supplied from the reference cell 30a. During the read operation, the comparator 26 generates data "0" if the read signal from the one input represents over-programmed state as compared to the read signal from the other input (e.g.  $I_{data} < I_{ref} - I_{offset}$ ), and data "1" if otherwise. A programming circuit 40 controls the programming of the reference cell 30, as well as each non-volatile memory cell within each subgroup 20.

In operation, the reference cell 30a and data cells in the subgroups 20(a-c) are first erased. The programming circuit 40 then weakly programs the reference cell 30a. The condition of this initial reference cell program operation is chosen so that the reference cell 30a is not to be over-programmed, as verified by a subsequent verification discussed below. The programming circuit 40 then softly programs each of the non-volatile memory data cells in the group 22a, with which the reference cell 30a is associated. Again, the condition of this initial data cell program operation is set so that the data cells are not to be over-programmed, as verified by a subsequent read discussed below. A read operation is performed on each of the data cells in subgroups 20(a-c) and on the refer-

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ence cell **30a**, and the read signals are compared by the comparators **26**. If any of the data cells is under programmed (i.e. data is “1”, corresponding to  $I_{data} > I_{ref} - I_{offset}$ ), then the programming circuit **40** is activated to further program the data cells which read “1”, while the data cells which read “0” are deselected to prevent them from being programmed further. When additional programming of the data cells occurs, the conditions of programming may be adjusted so that the rate of electron injection for programming is the same as previously, thereby maintaining a substantially constant rate of electron injection.

Alternatively, to save time, rather than programming all of the data memory cells in each of the subgroups **20(a-c)**, a select few (even as few as one) memory cells may be chosen from each subgroup **20(a-c)** to be programmed and compared at this step. After all chosen data cells are sufficiently programmed to read “0”, the programmed chosen data cells are read and the read signals are individually supplied to the source **60** to be measured. The median value  $I_{med}$  of the read signals from data cells associated with the same reference cell **30a**, is then calculated. The calculated median value  $I_{med}$  is numerically compared to a target value  $I_{Tdata}$ , which is the expected read signal from a typical programmed data cell which first passes verification with the target effective reference level  $I_T$ . The target value for a “typical programmed data cell”  $I_{Tdata}$  corresponds to slightly over-programmed charge state compared to the target effective reference level  $I_T$ , due to the finite change in data cell charge state after every program operation. Thus,  $I_{Tdata} = I_T - I_{overshoot}$ , the difference between  $I_T$  and  $I_{Tdata}$  can be derived from data cell programming characteristics. When  $I_{med}$  reaches  $I_{Tdata}$  the method stops. However, in the event  $I_{med}$  has not reached  $I_T$ , then the programming circuit **40** is activated to further program the reference cell **30a**. When additional programming of the reference cell occurs, the conditions of programming may be adjusted so that the rate of electron injection for programming is the same as previously, thereby maintaining a substantially constant rate of electron injection. A flow chart of this method is schematically shown in FIG. 3B. Other reference cells **30** in the circuit are programmed similarly. Programming of multiple reference cells can be done in parallel or in series. When reference cells are programmed in parallel, those reference cells which have passed verification are deselected to prevent them from being programmed further, while programming continues for those reference cells which have not passed verification.

Referring to FIG. 4A there is shown a block level diagram of the device **310** capable of performing the third method of the present invention. The device **310** is similar to the device **210** and the device **110** and device **10** and hence, like numerals will be used to designate like parts. The device **310** has an array **20** of non-volatile memory cells, divided into a plurality of subgroups of non-volatile memory cells **20(a-c)** formed in a group **22a**. Although only three subgroups **20(a-c)** are shown forming one subgroup **22a**, it is clear that there are other groups **22x**, with other subgroups **20** forming the array **20** of non-volatile memory cells. In addition, each subgroup, e.g. **20a** has an associated comparator **26a**. Finally a reference cell **30a** is associated with the group **22a** of non-volatile memory cells, similar to that described and shown in FIGS. 1, 2A, and 3A.

Read out from non-volatile memory cells from each subgroup, e.g. **20a** is supplied, along the bit line, to one input of the associated comparator, e.g. **26a**. In addition, the read out is supplied to a first source **60** such as an output bonding pad, such that the read-out may be measured. Another input to each of the comparators **26(a-c)** is supplied from the refer-

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ence cell **30a**. During read, the comparator **26** generates data “0” if the read signal from the one input represents over-programmed state as compared to the read signal from the other input (e.g.  $I_{data} < I_{ref} - I_{offset}$ ), and data “1” if otherwise. The reference cell **30a** may also be read out and supplied to a second source **62**, such as an output bonding pad, such that the read out of the reference cell **30a** may be measured. A programming circuit **40** controls the programming of the reference cell **30**, as well as each non-volatile memory cell within each subgroup **20**.

In operation, the reference cell **30a** and data cells in the subgroups **20(a-c)** are first erased. The programming circuit **40** then weakly programs the reference cell **30a**. The condition of this initial reference cell program operation is chosen so that the reference cell **30a** is not to be over-programmed, as verified by a subsequent verification discussed below. The reference cell **30a** is read and the signal level so read is supplied to the second source **62**, where the current/voltage is measured. The measured read signal from the reference cell **30a**  $I_{ref}$  is then numerically compared to a target level  $I_{T+}$ .  $I_{T+}$  is chosen to represent a slightly under-programmed charge state as compared to the target effective reference level  $I_T$ , i.e.  $I_{T+} > I_T$ , and  $(I_{T+} - I_T)$  is larger than expected  $I_{offset}$  generated by any of the comparators **26** in the circuit. If  $I_{ref} > I_{T+}$  then the programming circuit **40** is activated to further program the reference cell **30a**. When additional programming of the reference cell occurs, the conditions for programming may be adjusted so that the rate of electron injection for programming is the same as previously, thereby maintaining a substantially constant rate of electron injection. Once  $I_{ref}$  reaches  $I_{T+}$ , then the programming circuit **40** weakly programs each of the non-volatile memory data cells in the group **22a**, with which the reference cell **30a** is associated. The condition of this initial data cell program operation is chosen so that any of the data cells is not to be over-programmed, as verified by a subsequent read discussed below.

A read operation is performed on the data cells in each subgroup **20(a-c)** and on the reference cell **30a**, and the results are compared by the comparators **26**. If any of the data cells are under programmed, i.e. data is “1”, corresponding to  $I_{data} > (I_{ref} - I_{offset})$ , then the programming circuit **40** is activated to further program the data cells in the group **22a** which read data “1”, while data cells which read data “0” are deselected to prevent them from being programmed further. When additional programming of the data cells occurs, the conditions for programming may be adjusted so that the rate of electron injection for programming is the same as previously, thereby maintaining a substantially constant rate of electron injection. Alternatively, to save time, rather than programming all of the data memory cells in each of the subgroups **20(a-c)**, a select few (even as few as one) memory cell may be chosen from each subgroup **20(a-c)** to be programmed and compared at this step. After all chosen data cells are sufficiently programmed to read “0”, the programmed data cells are read and the read signals are individually supplied to the source **60** to be measured. The median value  $I_{med}$  of the read signals from chosen data cells associated with the same reference cell **30a**, is then calculated. The calculated median value  $I_{med}$  is used to define a read signal target  $I_{T'}$  for the reference cell **30a**, where  $I_{T'} = I_T - I_{T+} + I_{med} + I_{overshoot}$ . Once  $I_{T'}$  is defined and calculated, the reference cell **30a** is then further programmed by the programming circuit **40**. The reference cell **30a** is read and the signal level so read is supplied to the second source **62**, where the read signal is measured. The measured read signal from the reference cell **30a**  $I_{ref}$  is then numerically compared to the target level  $I_{T'}$ . In the event the reference cell **30a** is under programmed, i.e.  $I_{ref} > I_{T'}$  then the



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programming circuit is activated again to further program the reference cell 30a. When additional programming of the data cells occurs, the conditions for programming may be adjusted so that the rate of electron injection for programming is the same as previously, thereby maintaining a substantially constant rate of electron injection. In the event the reference cell 30a has reached the target  $I_T$ , i.e.  $I_{ref} < I_T$ , then the method ends. A flow chart of this method is schematically shown in FIG. 4B. Other reference cells 30 in the circuit are programmed similarly. Programming of multiple reference cells can be done in parallel or in series. When reference cells are programmed in parallel, those reference cells which have passed verification are deselected to prevent them from being programmed further, while programming continues for those reference cells which have not passed verification.

What is claimed is:

1. A method of programming a first plurality of reference cells in a memory device having an array of non-volatile memory cells and a second plurality of comparators, comprising:

(i) programming one of said first plurality of reference cells;

(ii) reading a current of said programmed reference cell and comparing same to a current reference signal using each of said second plurality of comparators; wherein the second plurality of comparators is associated with said one programmed reference cell

(iii) further programming of said one said first plurality of reference cells based upon said comparison; and repeating the steps of (i)-(iii) for a different one of said first plurality of reference cells, and its associated comparators, until all of said first plurality of reference cells are programmed.

2. The method of claim 1, further comprising:

deselecting a verified reference cell among said first plurality of reference cells when the verified reference cell has passed verification after step (ii); and

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wherein the step of continuing (iii) continues the programming of reference cells which have not been deselected.

3. The method of claim 1 wherein said continuing of programming is done by adjusting program conditions so as to maintain a substantially constant rate of electron injection.

4. The method of claim 1 wherein said one of said first plurality of reference cells is associated with a third plurality of comparators, wherein said third plurality of comparators is a subset of said second plurality of comparators, and said reading step reads a current of each of said programmed reference cells and the read signal is compared to a current reference signal for each one of said third plurality of comparators.

5. The method of claim 4 wherein the programming of said one of said first plurality of reference cells is continued in the event the reading of more than one half of said third plurality of comparators shows the reference cell is under programmed.

6. The method of claim 1, wherein each reference cell from the first plurality of reference cells has an associated different comparator from the second plurality of comparators.

7. A system for programming a reference cell, comprising:

a programming circuit coupled to a reference cell;

a current reference signal;

a switch; and

a plurality of comparators, wherein each comparator is coupled to the current reference signal through the switch, wherein each comparator is further coupled to the reference cell,

wherein the programming circuit alters the reference cell in response to the outputs of the comparators.

8. The system of claim 7, further comprising:

a first plurality of memory cells coupled to one of said plurality of comparators.

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